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Application/Control No.	Applicant(s)/Patent under Reexamination
09/955,764	LI ET AL.
Examiner	Art Unit
J. Derek Rutten	2192

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - see search history printout	11/29/2005	JDR
717/130; 719/315,316; 709/201 -text search only - see search history printout	11/29/2005	JDR